

The GreenMOS® high voltage MOSFET utilizes charge balance technology to achieve outstanding low on-resistance and lower gate charge. It is engineered to minimize conduction loss, provide superior switching performance and robust avalanche capability.

The GreenMOS® Z series is integrated with fast recovery diode (FRD) to minimize reverse recovery time. It is suitable for resonant switching topologies to reach higher efficiency, higher reliability and smaller form factor.

- Low $R_{DS(ON)}$ & FOM
- Extremely low switching loss
- Excellent stability and uniformity
- Ultra-fast and robust body diode

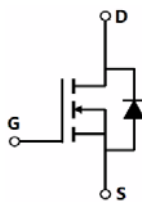
- PC power
- Telecom power
- Server power
- EV Charger
- Motor driver



$V_{DS, min} @ T_{j(max)}$	600	V
----------------------------	-----	---

	108	m
Q_g	37.1	nC

OSG55R108KZF	TO263	OSG55R108KZ
--------------	-------	-------------



at $T_j=25^\circ\text{C}$ unless otherwise noted

Drain-source voltage	V_{DS}	550	V
Gate-source voltage	V_{GS}	± 30	V
Continuous drain current ¹⁾ , $T_C=25^\circ\text{C}$	I_D	30	A
Continuous drain current ¹⁾ , $T_C=100^\circ\text{C}$		19	
Pulsed drain current ²⁾ , $T_C=25^\circ\text{C}$	$I_{D, pulse}$	90	A
Continuous diode forward current ¹⁾ , $T_C=25^\circ\text{C}$	I_S	30	A
Diode pulsed current ²⁾ , $T_C=25^\circ\text{C}$	$I_{S, pulse}$	90	A
Power dissipation ³⁾ , $T_C=25^\circ\text{C}$	P_D	219	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	1000	mJ
MOSFET dv/dt ruggedness, $V_{DS}=0\dots 480\text{ V}$	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS}=0\dots 480\text{ V}$, $I_{SD} = I_D$	dv/dt	50	V/ns
Operation and storage temperature	T_{stg}, T_j	-55 to 150	$^\circ\text{C}$

Thermal resistance, junction-case	R_{JC}	0.57	$^\circ\text{C/W}$
Thermal resistance, junction-ambient ⁴⁾	R_{JA}	62	$^\circ\text{C/W}$

 at $T_j=25^\circ\text{C}$ unless otherwise specified

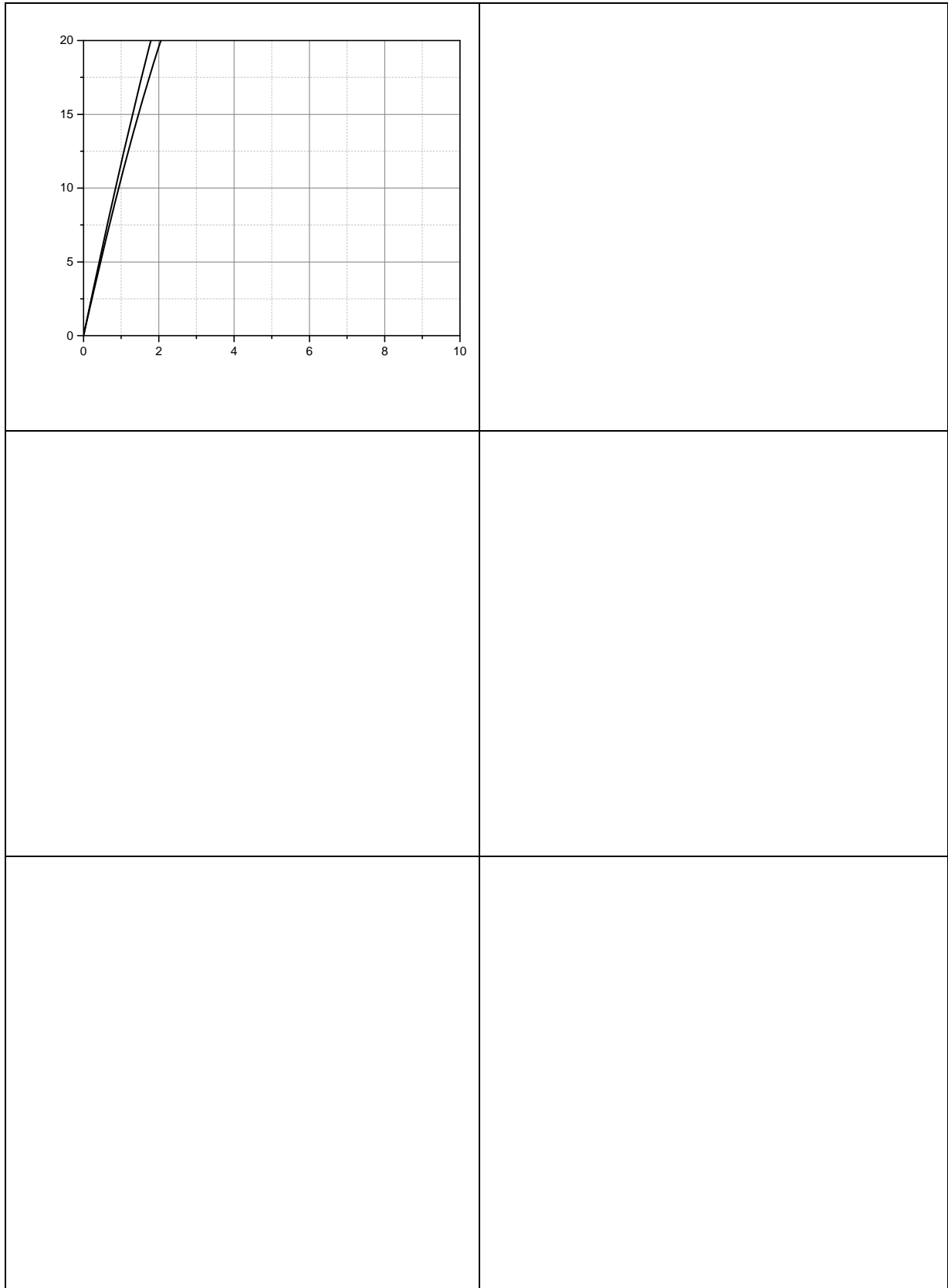
Drain-source breakdown voltage	BV_{DSS}	550		V	$V_{GS}=0\text{ V}$, $I_D=1\text{ mA}$
		600			$V_{GS}=0\text{ V}$, $I_D=1\text{ mA}$, $T_j=150^\circ\text{C}$
Gate threshold voltage	$V_{GS(th)}$	3.0	4.5	V	$V_{DS}=V_{GS}$, $I_D=1\text{ mA}$
Drain-source on-state resistance	$R_{DS(ON)}$		0.085	0.108	$V_{GS}=10\text{ V}$, $I_D=15\text{ A}$
			0.2		$V_{GS}=10\text{ V}$, $I_D=15\text{ A}$, $T_j=150^\circ\text{C}$
Gate-source leakage current	I_{GSS}			100	$V_{GS}=30\text{ V}$
				-100	$V_{GS}=-30\text{ V}$
Drain-source leakage current	I_{DSS}		10	μA	$V_{DS}=550\text{ V}$, $V_{GS}=0\text{ V}$
Gate resistance	R_G		24		$f=1\text{ MHz}$ Open drain

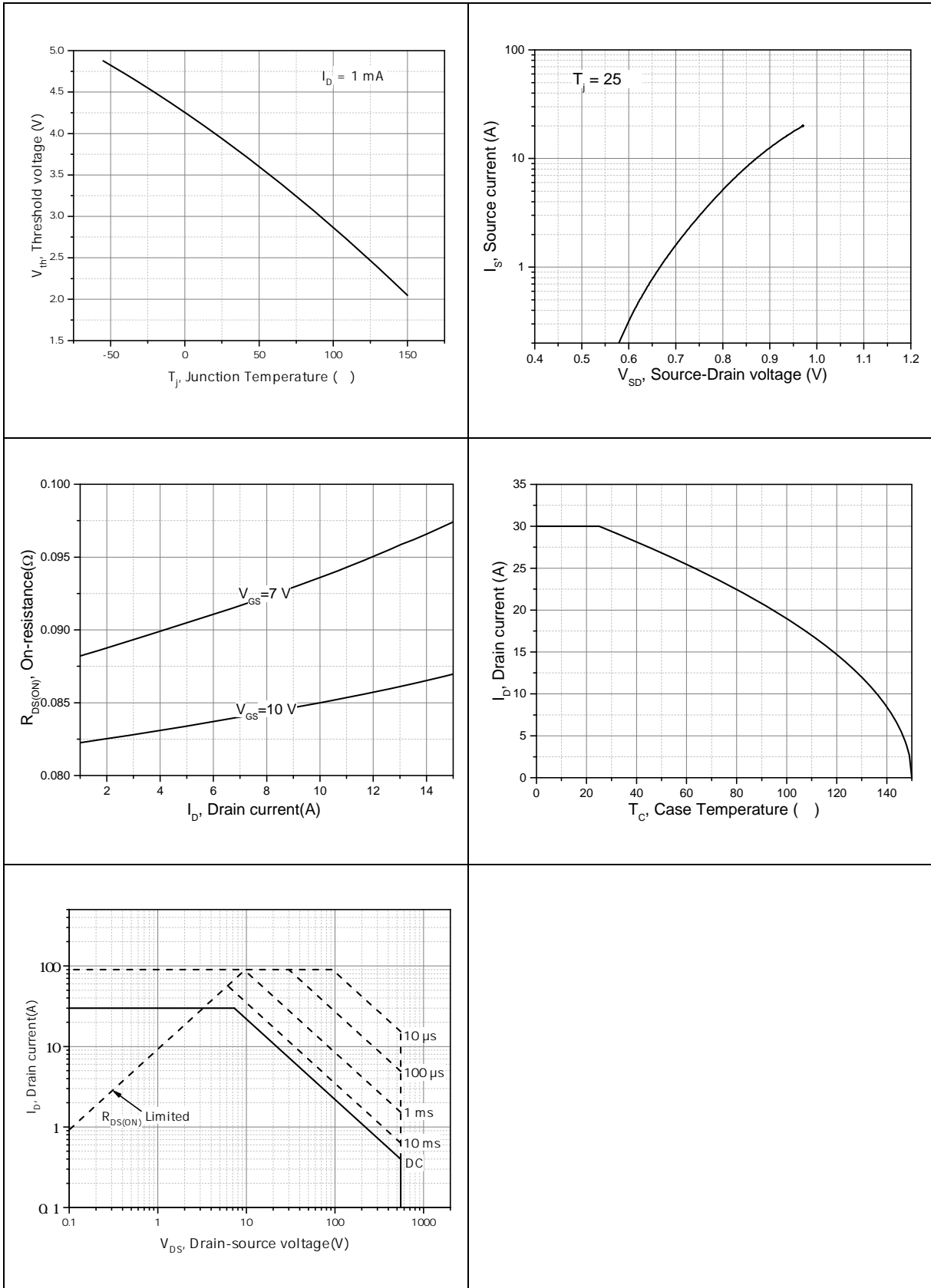
Input capacitance	C_{iss}	2674.5	pF	$V_{GS}=0\text{ V}$, $V_{DS}=50\text{ V}$, $f=100\text{ KHz}$
Output capacitance	C_{oss}	246	pF	
Reverse transfer capacitance	C_{rss}	9.6	pF	
Turn-on delay time	$t_{d(on)}$	67.4	ns	$V_{GS}=10\text{ V}$, $V_{DS}=400\text{ V}$, $R_G=2\ \Omega$, $I_D=16\text{ A}$
Rise time	t_r	71.1	ns	
Turn-off delay time	$t_{d(off)}$	103.9	ns	
Fall time	t_f	33.4	ns	

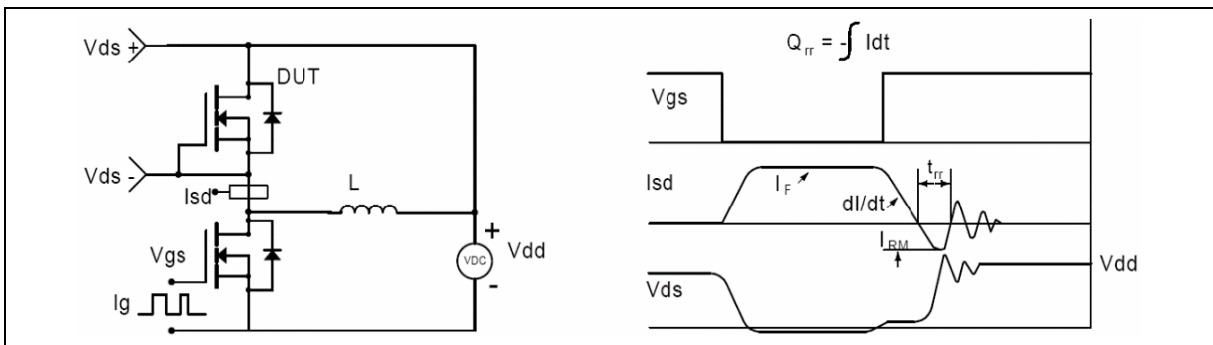
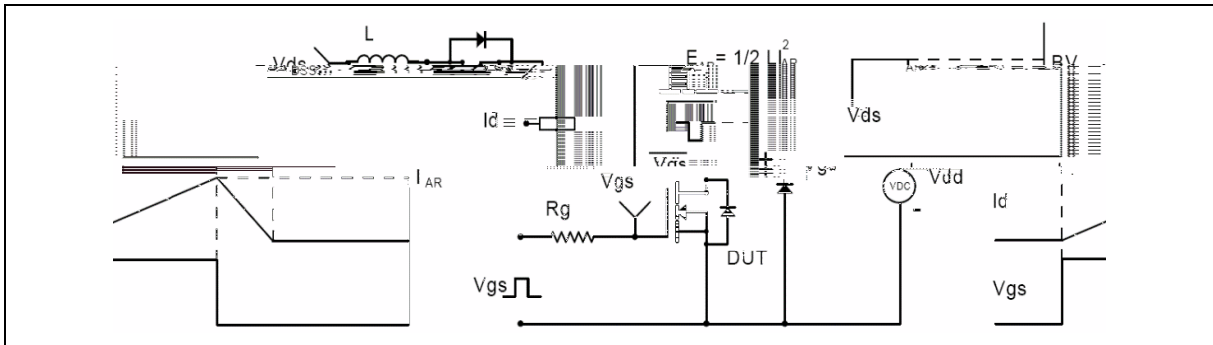
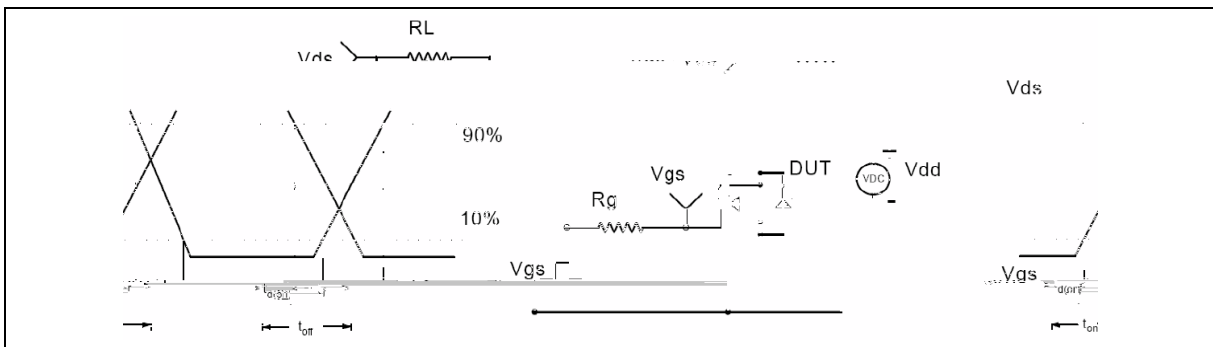
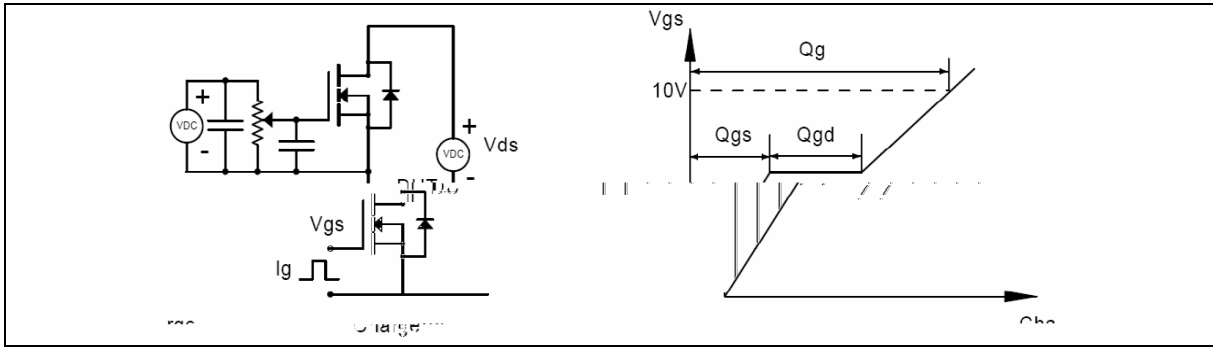
Total gate charge	Q_g	37.1	nC	$V_{GS}=10\text{ V}$, $V_{DS}=400\text{ V}$, $I_D=16\text{ A}$
Gate-source charge	Q_{gs}	11	nC	
Gate-drain charge	Q_{gd}	13.8	nC	
Gate plateau voltage	$V_{plateau}$	6.7	V	

Diode forward voltage	V_{SD}	1.4	V	$I_S=30\text{ A}$, $V_{GS}=0\text{ V}$
Reverse recovery time	t_{rr}	123	ns	$I_S=16\text{ A}$, $di/dt=100\text{ A}/\mu\text{s}$
Reverse recovery charge	Q_{rr}	0.73	μC	
Peak reverse recovery current	I_{rrm}	11	A	

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) P_d is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of R_{JA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25\text{ }^\circ\text{C}$.
- 5) $V_{DD}=100\text{ V}$, $V_{GS}=10\text{ V}$, $L=60\text{ mH}$, starting $T_j=25\text{ }^\circ\text{C}$.







Symbol	mm
--------	----

TO263-C	800	1	800	5	4000

OSG55R108KZF	TO263	yes	yes	yes

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Oriental Semiconductor hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

For further information on technology, delivery terms and conditions and prices, please contact the Oriental Semiconductor sales representatives (www.orientalsemi.com).

